



- Fast precise monitoring of SAW device fabrication
- Simple probe measurements of PCMs delivers CTQ data
 - IDT Metal Thickness
 - IDT Line Width
 - Conductivity
 - IDT Sidewall Angle
- Provides dimensional information across an entire wafer
- Not sensitive to measurement parasitics
- Non-destructive process

APPLICATIONS

- New Process Startup
- New Product Design
- Quality Assurance
- Yield Improvement
- Process Control

REPLACES

- Profilometers
- CD-SEM
- XRR/XRF
- FIB SEM / TEM

AVAILABILITY

- Cloud Software Service
- Available Immediately
- Worldwide

- No Capital Investment
- Rapid Deployment
- Minimal Operator Training Required



PMTX

WaveX™

**Process
Monitoring
Toolset**